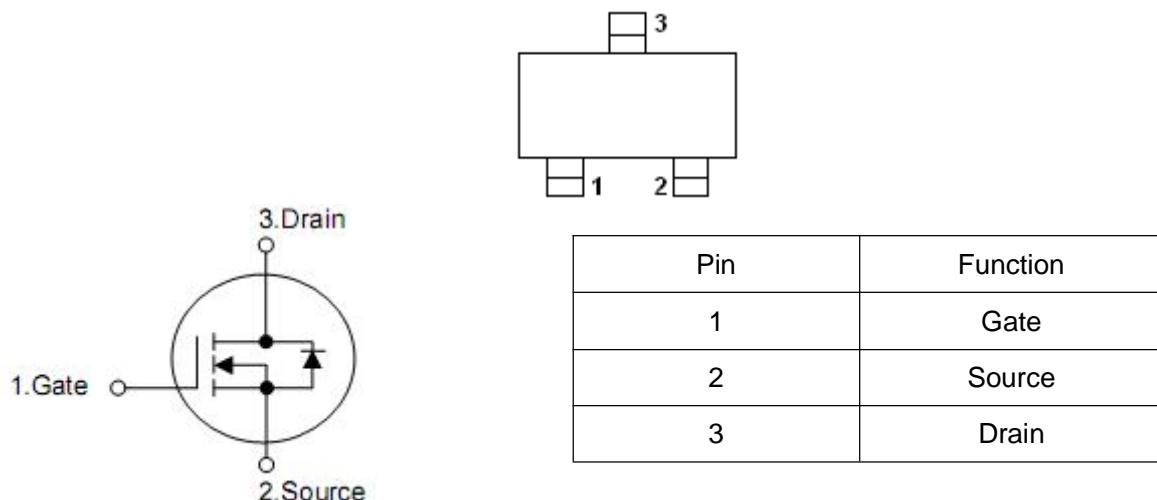


1. Features

- $V_{DS}=30V, R_{DS(on)}=0.055\Omega @ V_{GS}=10V, I_D=2.5A$
- $V_{DS}=30V, R_{DS(on)}=0.080\Omega @ V_{GS}=4.5V, I_D=2.0A$
- Power MOSFET
- 100% R_g tested

2. Symbol



3. Absolute maximum ratings

($T_A=25^\circ C$, unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DS}	30	V
Gate-source voltage	V_{GS}	± 12	V
Drain current continuous ($T_J=150^\circ C$) ^{a, b}	I_D	2.5	A
		2.0	
Pulsed drain current ^a	I_{DM}	10	
Continuous source current (diode conduction) ^{a, b}	I_S	1.25	
Power dissipation ^{a, b}	P_D	1.25	W
		0.8	
Junction and storage temperature range	T_J, T_{STG}	-55 to 150	°C

Parameter	Symbol	Typ	Max	Units
Maximum junction-ambient ^a	R_{thJA}	-	100	°C/W
		166	-	

Notes

- a. Surface mounted on FR4 board,
- b. $t \leq 5$ sec.

4. Electrical characteristics

($T_A=25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Static						
Drain-source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{DS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
Gate threshold voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1	-	-	V
Gate- body leakage	I_{GSS}	$V_{\text{GS}}=\pm 12\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Zero gate voltage drain current	I_{DSS}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
On-state drain current ^a	$I_{\text{D}(\text{on})}$	$V_{\text{DS}} \geq 4.5\text{V}, V_{\text{GS}}=10\text{V}$	6	-	-	A
		$V_{\text{DS}} \geq 4.5\text{V}, V_{\text{GS}}=4.5\text{V}$	4	-	-	
Static drain-source on-resistance ^a	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=2.5\text{A}$	-	-	0.055	Ω
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=2.0\text{A}$	-	-	0.080	
Forward transconductance ^a	g_{fs}	$V_{\text{DS}}=4.5\text{V}, I_{\text{D}}=2.5\text{A}$	-	4.8	-	S
Diode forward voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=1.25\text{A}$	-	0.77	1.2	V
Dynamic^b						
Total gate charge	Q_g	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=5\text{V}, I_{\text{D}}=2.5\text{A}$	-	2.4	4	nC
Total gate charge	Q_{gt}	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=10\text{V}$ $I_{\text{D}}=2.5\text{A}$	-	4.5	10	
Gate-source charge	Q_{gs}		-	0.8	-	
Gate-drain charge	Q_{gd}		-	1.0	-	
Input capacitance	C_{iss}	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	240	-	pF
Output capacitance	C_{oss}		-	110	-	
Reverse transfer capacitance	C_{rss}		-	17	-	
Switching						
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=15\text{V}, I_{\text{D}}=1\text{A}, R_{\text{L}}=15\Omega, R_{\text{G}}=6\Omega, V_{\text{GEN}}=10\text{V}$	-	8	20	ns
Rise time	t_r		-	12	30	
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	17	35	
Fall time	t_f		-	8	20	

Notes

- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

5. Test circuits and waveforms

